



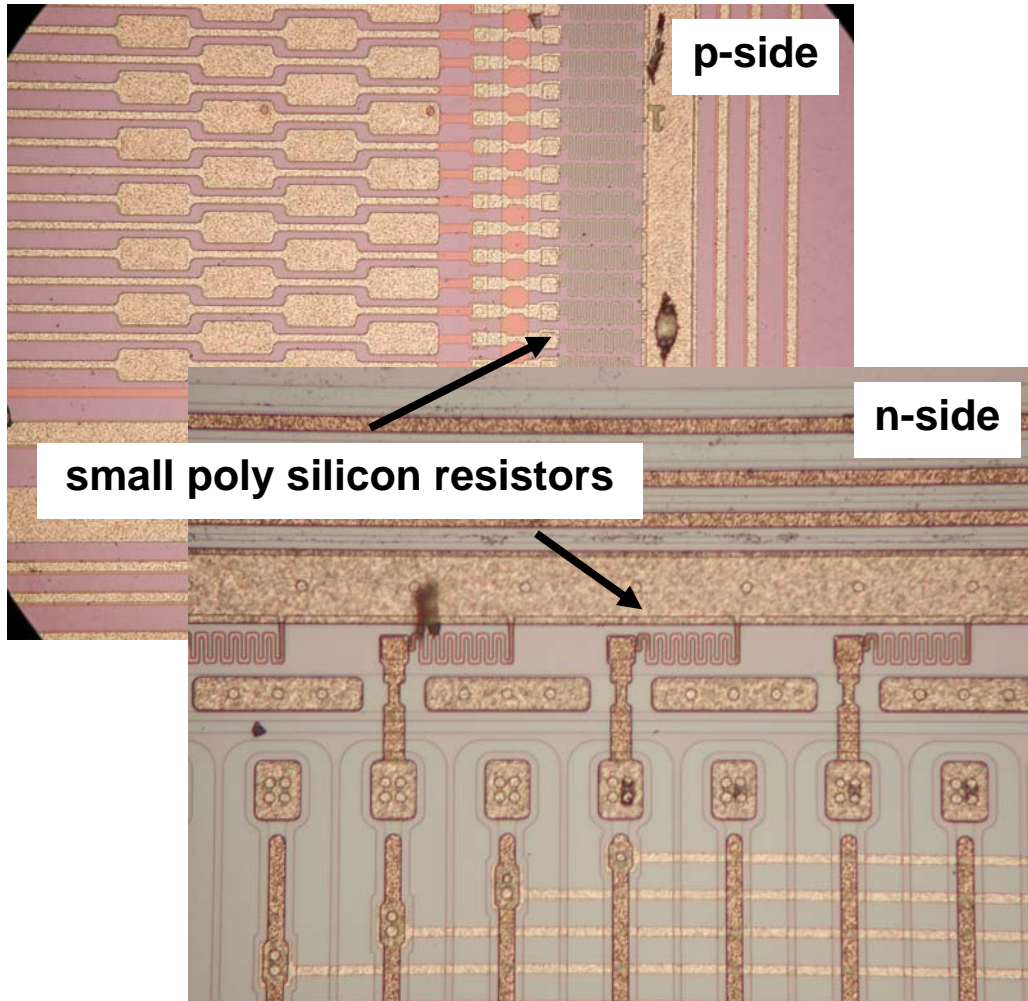
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# Results of the SPS Beam Test @ CERN

C. Irmler (HEPHY Vienna)

- ⊗ **Micron Sensor**
- ⊗ **Beam Test Setup**
- ⊗ **Results**

## Micron Sensor - Overview



**Type:** DDD5  
used for D0 @ Fermilab

**Size:** 120 mm x 21 mm  
300  $\mu\text{m}$  thick  
 $V_{\text{depl}} = \text{max. } 50 \text{ V}$   
 $R_{\text{poly}} = 2.5 \text{ M}\Omega$

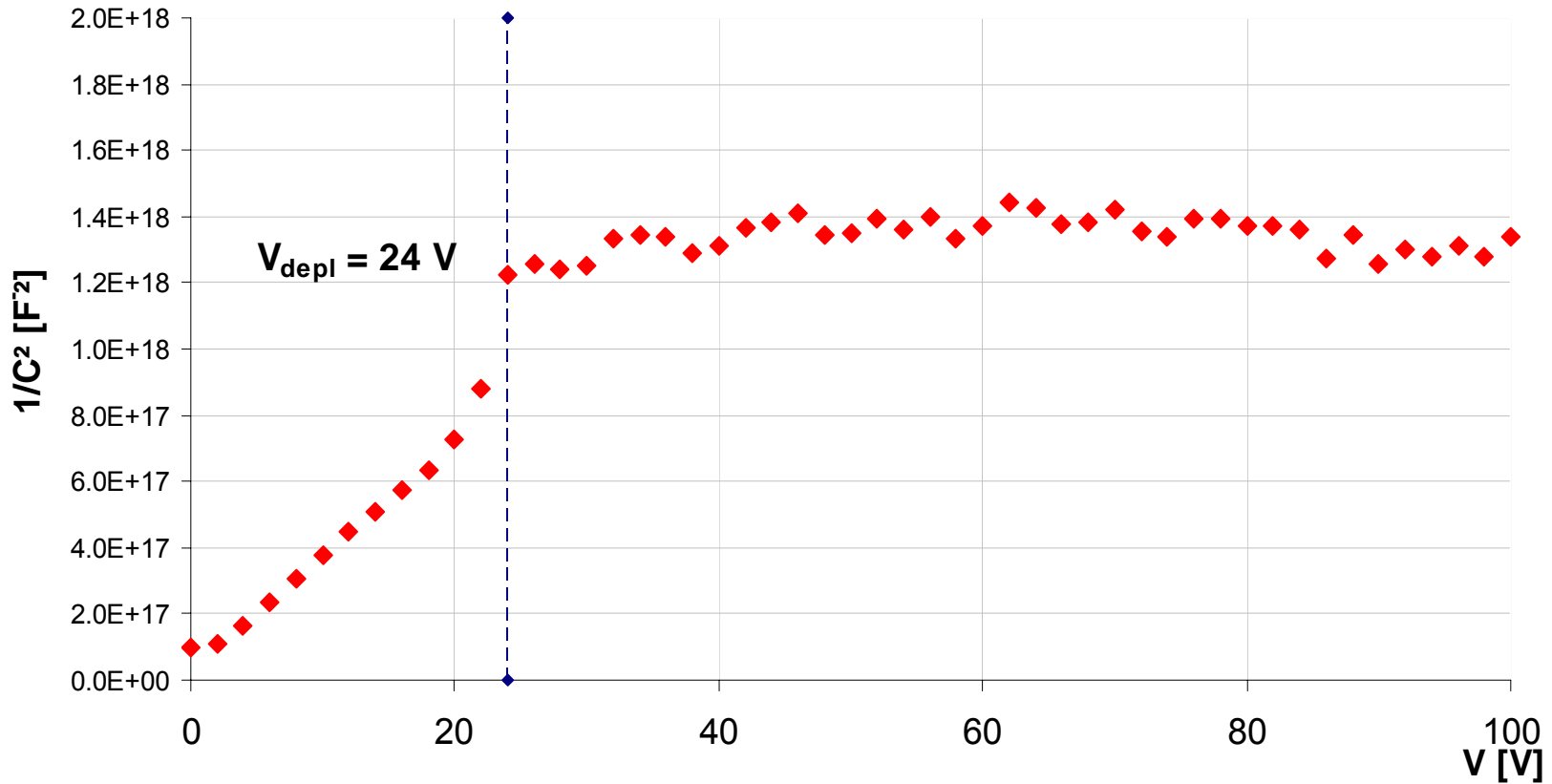
**p-side:** 384 strips  
50  $\mu\text{m}$  pitch  
w/o intermediate strip

**n-side:** 768 strips  
153.5  $\mu\text{m}$  pitch

double metal layer  
384 readout strips  
40.5  $\mu\text{m}$  readout pitch

# Micron Sensor – CV Curve

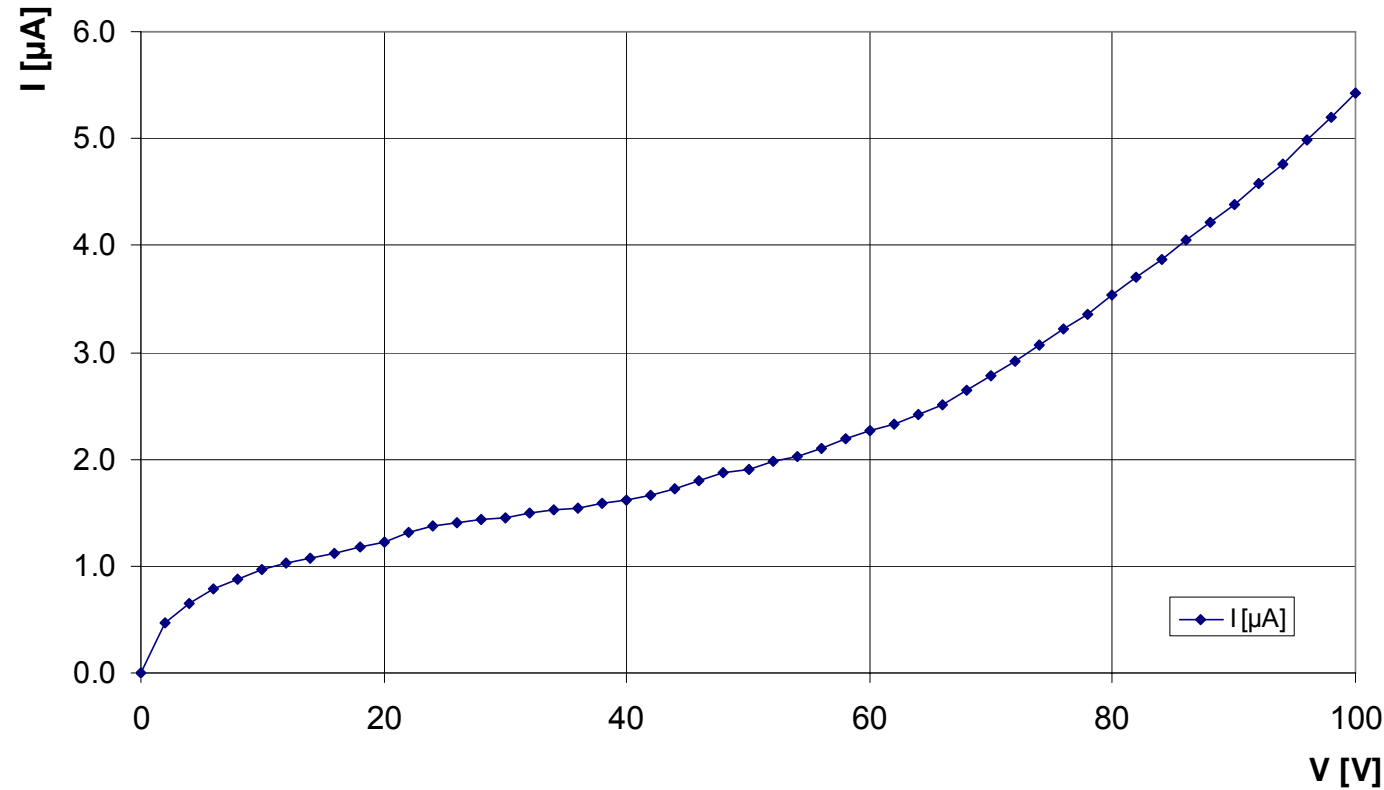
CV Curve - Micron DDD5



⊗  $V_{\text{depl}} = 24$  V (step before depletion, linear fit does not work)

# Micron Sensor – IV Curve

IV Curve - Micron DDD5



High  $I_{\text{bias}}$



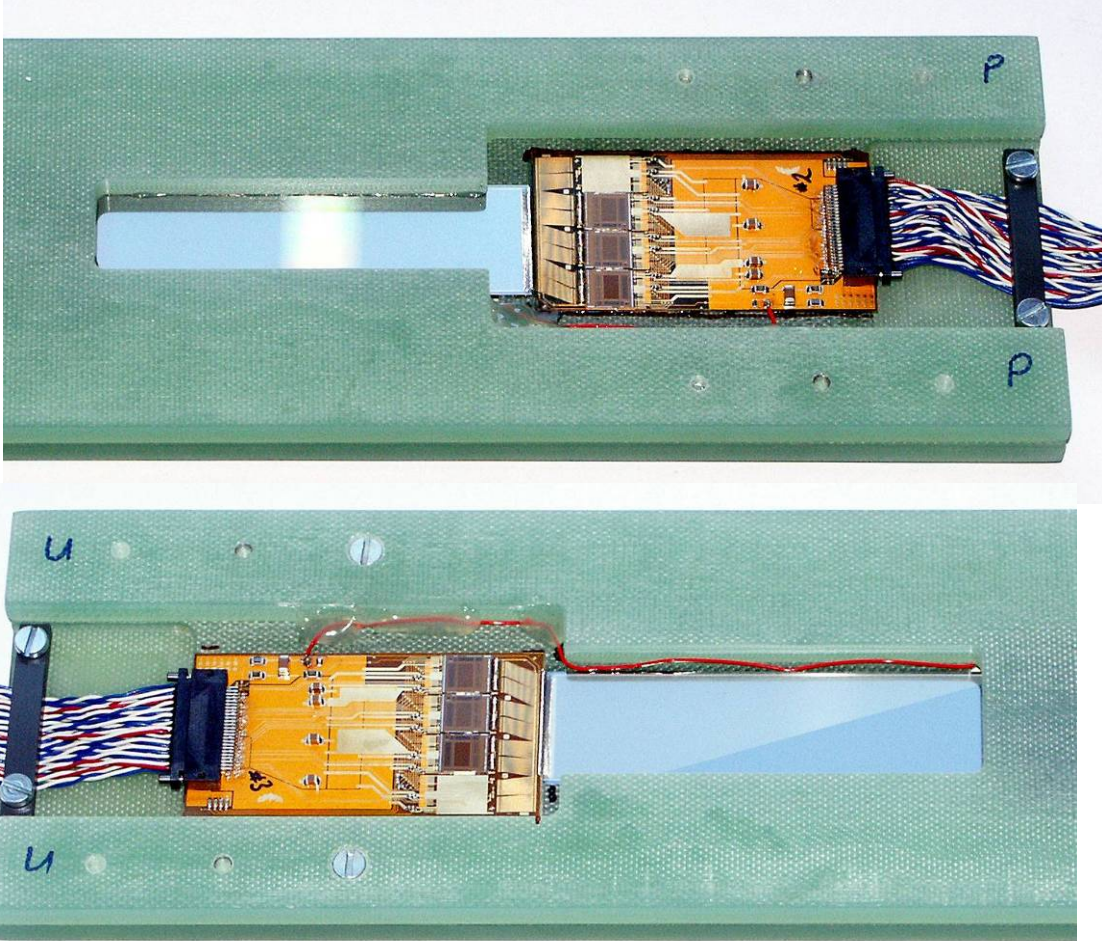
1.38  $\mu\text{A}$  @  $V_{\text{depl}}$



Slope increases above 60 V

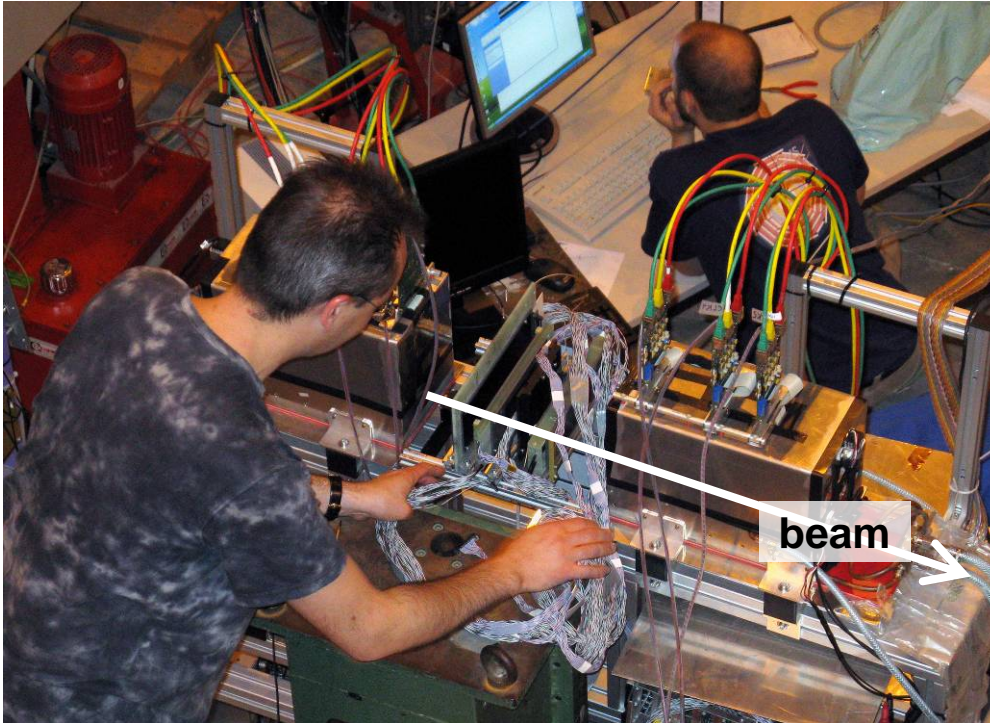


## Micron Sensor Module



- ⊗ Micron DDD5
- ⊗ Each side read out by three APV25 chips (384 channels)
- ⊗ Flex hybrids with integrated pitch adaptor
- ⊗ On n-side the hybrid is glued onto the sensor.

## Beam Test Setup



Beam test was performed @ CERN together with the SiLC beam test of our semiconductor group  
→ see yesterday's talk by T. Bergauer.

### Beam setup:

- ⊗ 120 GeV/c
- ⊗  $\pi^+ / p / K^+$   
(55.67% / 38.95% / 5.38%)

### Readout:

- ⊗ SVD3 readout system  
→ see previous talk by M. Friedl

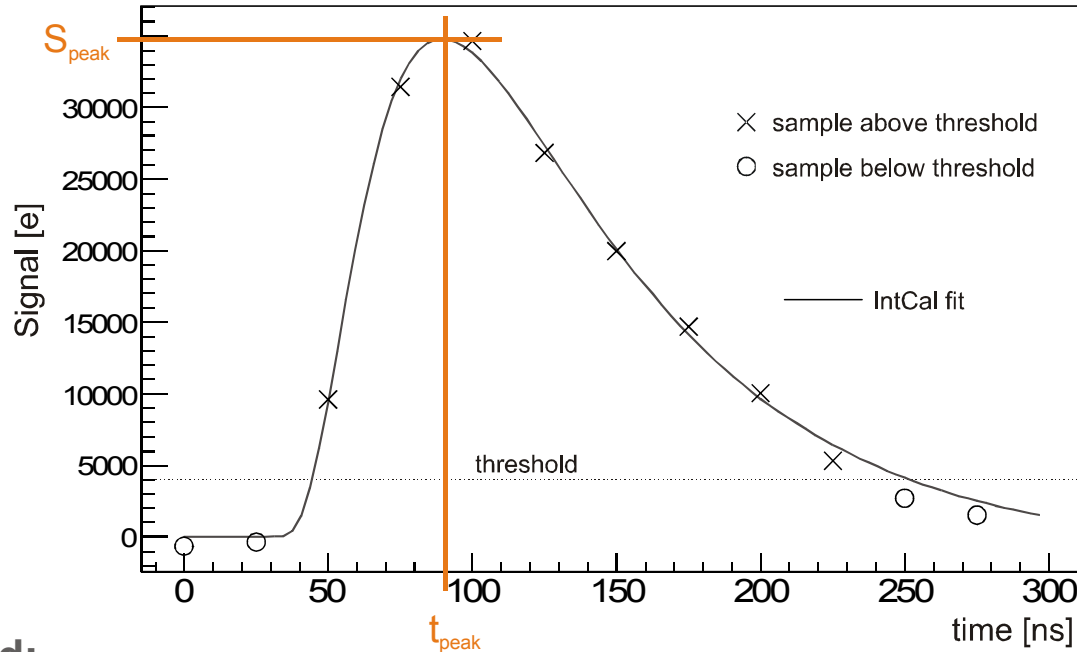
### Installed Modules:

- ⊗ JP module (2007)  
2 x SVD3 DSSD (partially ganged)
- ⊗ **Micron module (new)**
- ⊗ UV module  
UV triplet sensor (2005)
- ⊗ Flex module (2006)  
SVD3 DSSD (chip on sensor)
- ⊗ EUDET telescope

## Analysis Chain

- ⊗ Pedestal subtraction
- ⊗ Common mode correction
- ⊗ 2D-clustering (space and time)
- ⊗ Calculate cluster signal for each sample
  
- ⊗ Perform hit time reconstruction  
→ see previous talk by M. Friedl
- ⊗ Obtain timing, signal and noise

## Hit Time Reconstruction



### Method:

- ☒ Multiple samples around the peak are recorded (6 samples at this beam test) .
- ☒ Cluster signal for each sample is calculated.
- ☒ Fit function is applied to each waveform to obtain amplitude and timing.
- ☒ Reference waveform is taken from internal calibration of the APV25 chip.
- ☒ **Already explained by M. Friedl**



## Beam Test Results (Preliminary)

	Micron		JP single		JP ganged		UV		Flex	
	p-side	n-side	p-side	n-side	p-side	n-side	p-side	n-side	p-side	n-side
Average cluster width	<b>1.67</b>	<b>1.13</b>	2.31	1.92	2.10	1.76	2.21	1.88	2.28	1.91
Cluster SNR	<b>12.6</b>	<b>15.1</b>	12.7	13.9	8.5	10.5	23.6	24.0	13.8	18.4
Single SNR	<b>16.3</b>	<b>16.0</b>	19.3	19.2	12.3	13.9	35.1	32.8	20.9	25.4
Time resolution [ns]	<b>3.89</b>	<b>3.04</b>	3.49	2.74	5.24	4.30	2.55	1.16	3.50	1.90

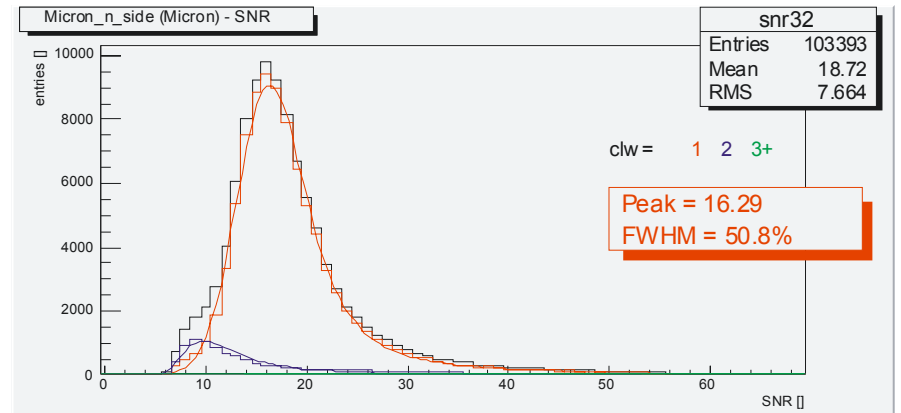
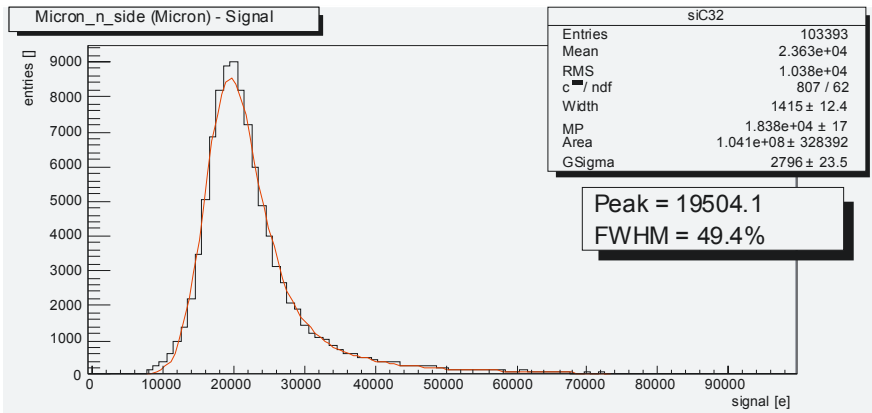
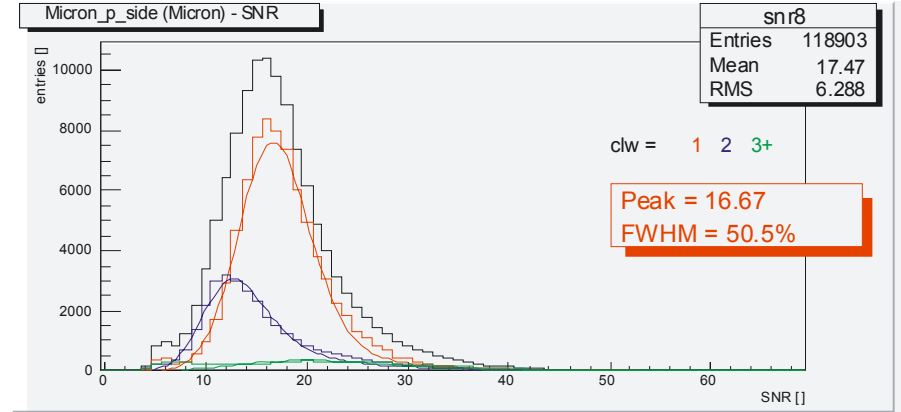
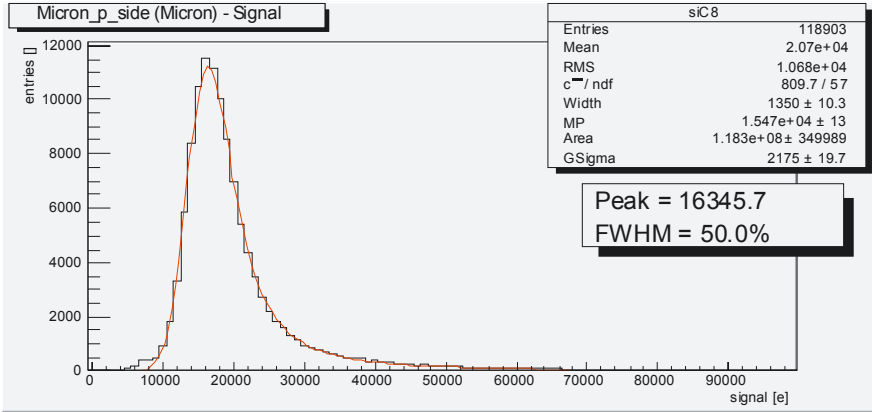
### Definitions:

- ⊗ Cluster SNR := Cluster Signal / ( Strip Noise \* sqrt (Cluster width) )
- ⊗ Single SNR := Cluster Signal / Strip Noise

### Results:

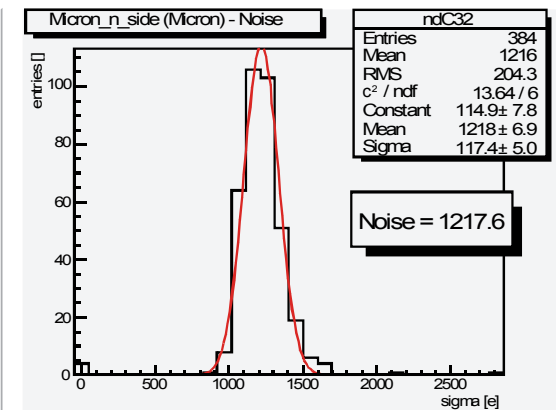
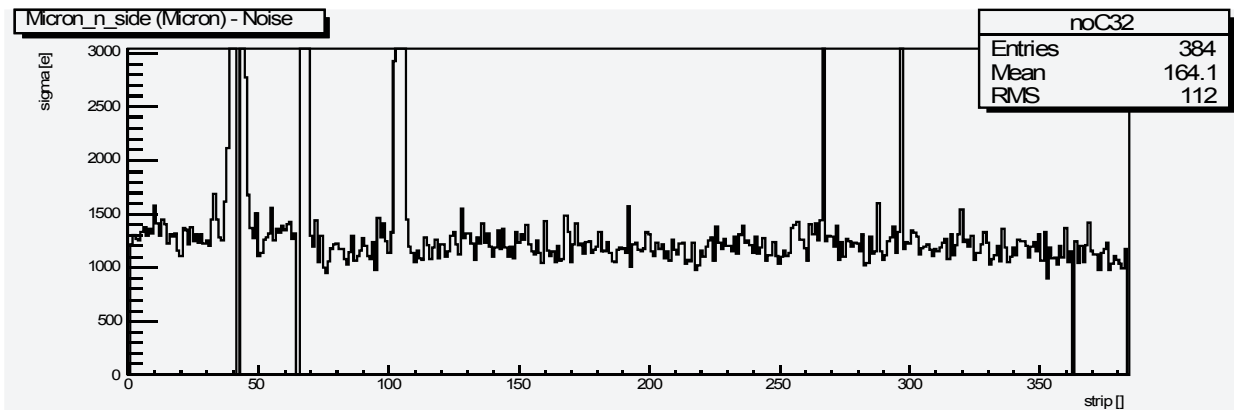
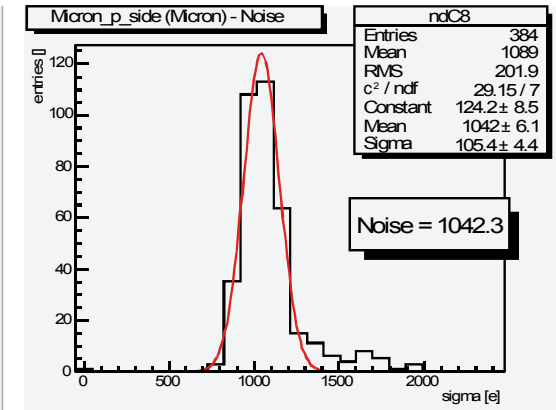
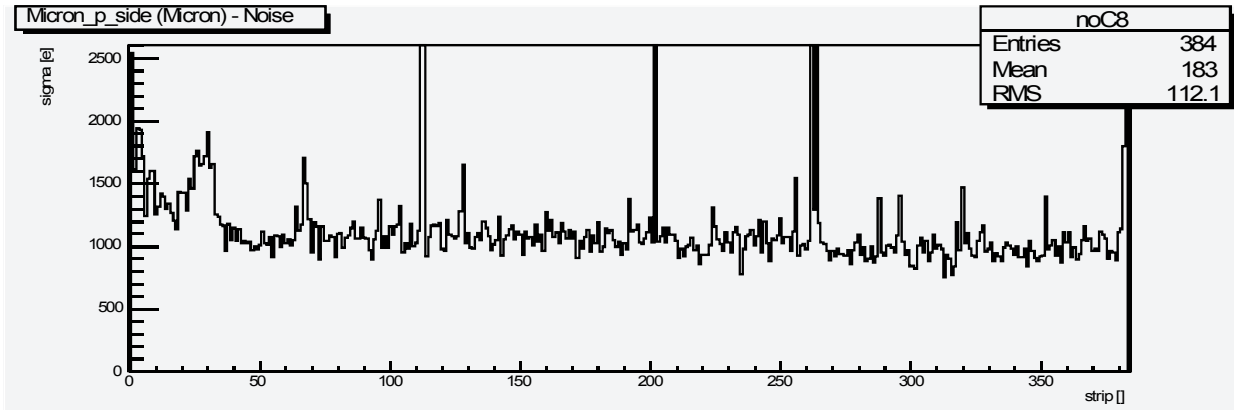
- ⊗ SNR of the Micron module is good and within the range of the other modules.
- ⊗ Micron has lower cluster width (no intermediate strips).
- ⊗ Effect of the 2<sup>nd</sup> metal layer on n-side is less than that of the long strips on p-side.
  
- ⊗ Poor SNR for JP module with ganged sensors → chip on sensor (M. Friedl).

# Micron Module - Signal Distribution



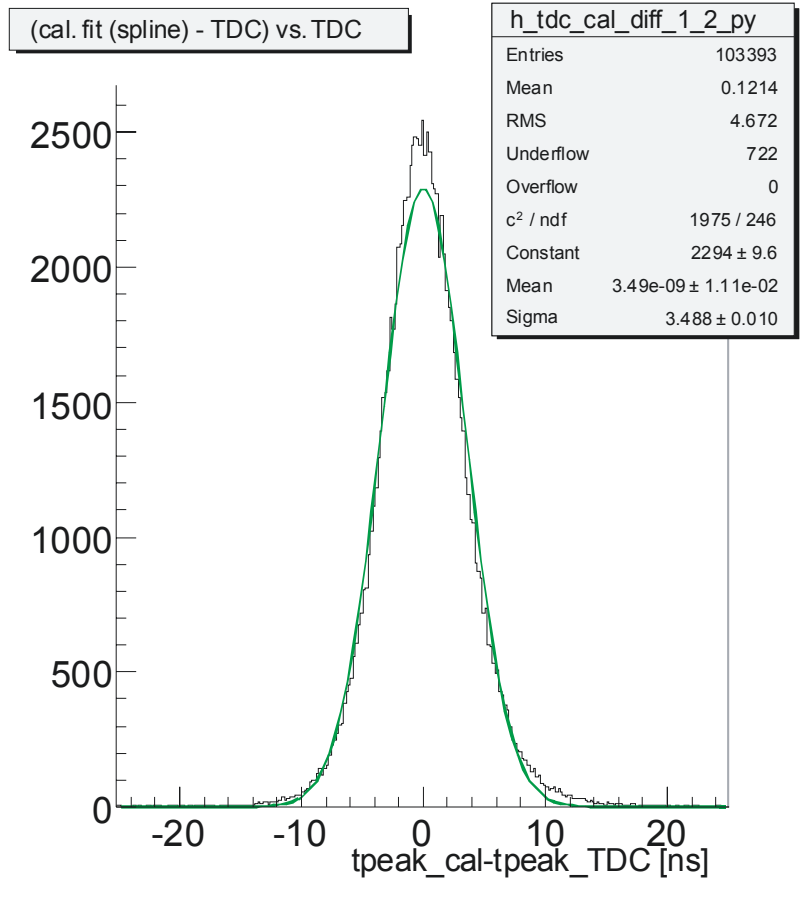
⊗ Signal has pretty Landau distribution; SNR depends on cluster width

## Micron Module - Noise

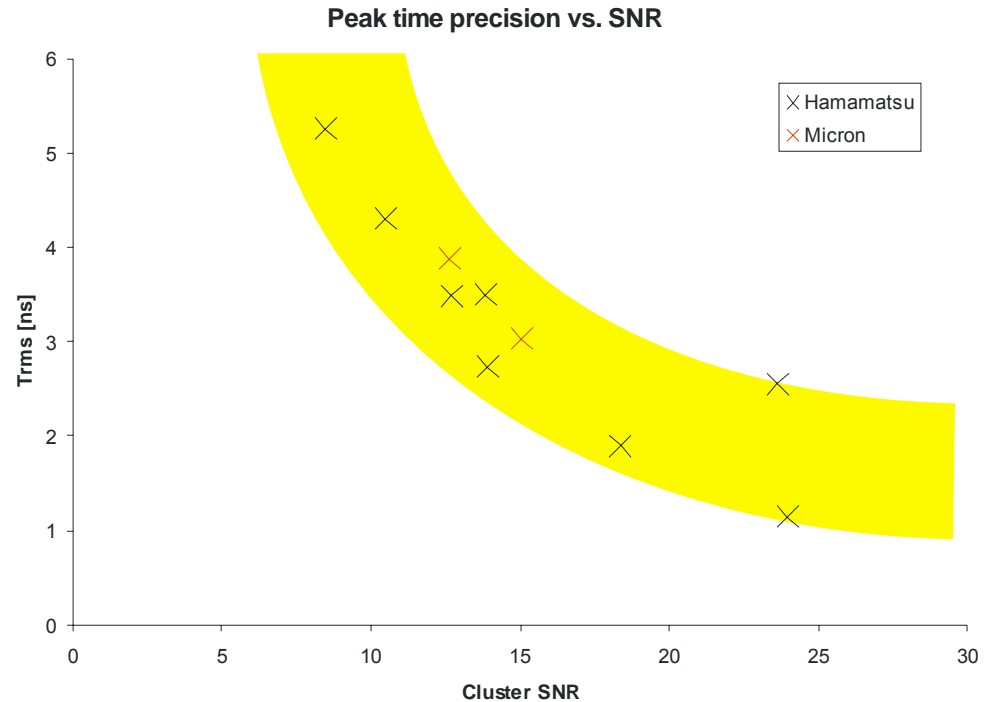


⊗ Few noisy strips on both sides of the sensor.

# Micron Module – Time Resolution (Preliminary)



TDC error ~ 1.71 ns



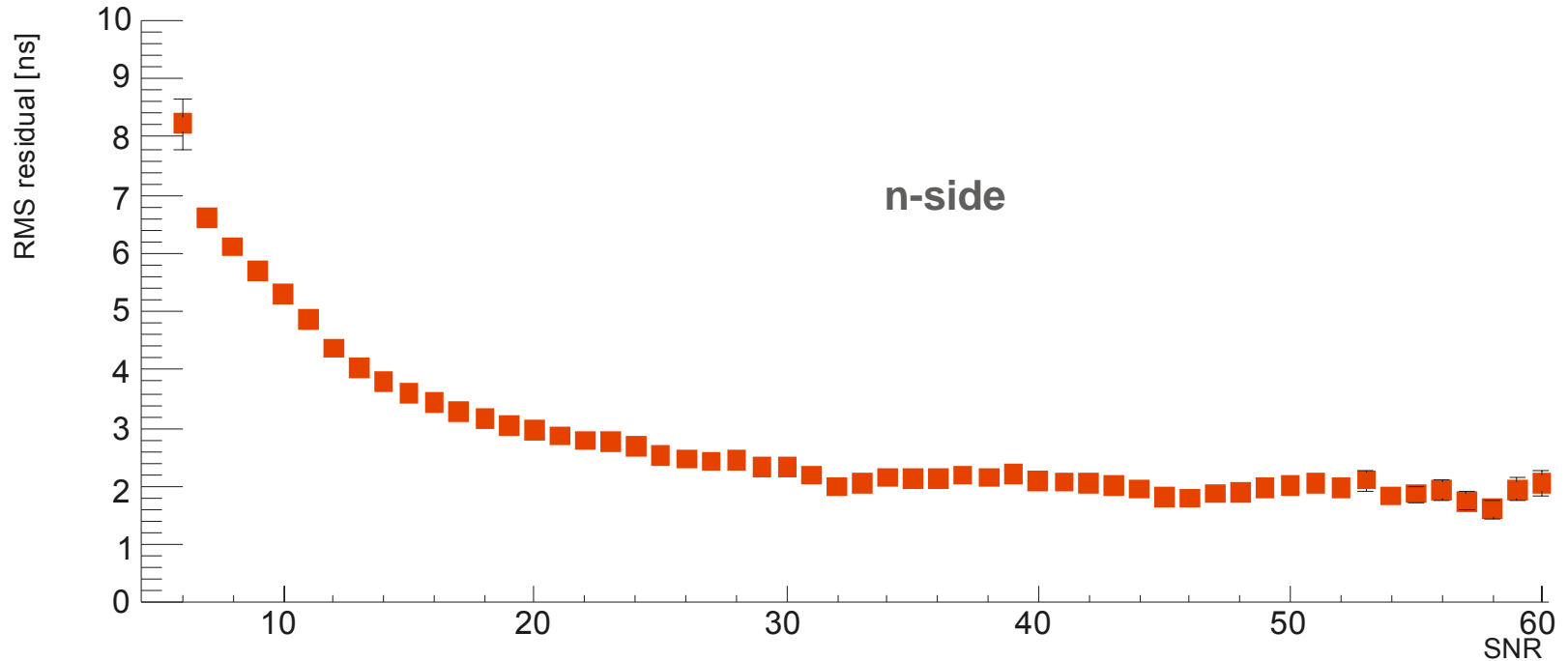
⊗ p-side: 3.89 ns

⊗ n-side: 3.04 ns

⊗ strongly depends on SNR

# Micron Module – Time Resolution vs. SNR

Cal fit (spline) RMS residuals vs. SNR





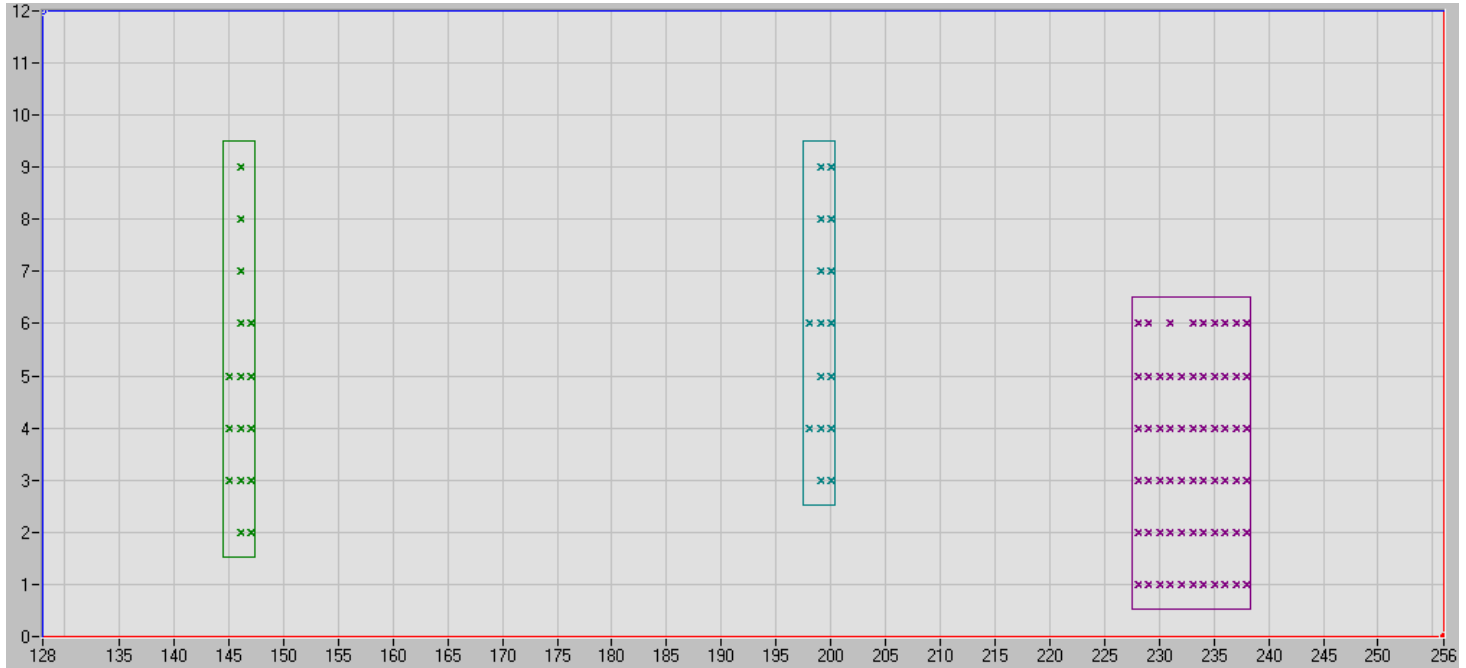
# Summary

- ⊗ Testbeam performed to evaluate Micron DDD5 sensor.
- ⊗ Minor deviations of CV and IV curve observed.
- ⊗  $I_{\text{bias}}$  above 1  $\mu\text{A}$
- ⊗ Few noisy strips detected.
  
- ⊗ SNR within the expected range.
- ⊗ Time resolution corresponds to SNR.
- ⊗ Noise contribution of the second metal layer is less than expected.

Thank you for your attention

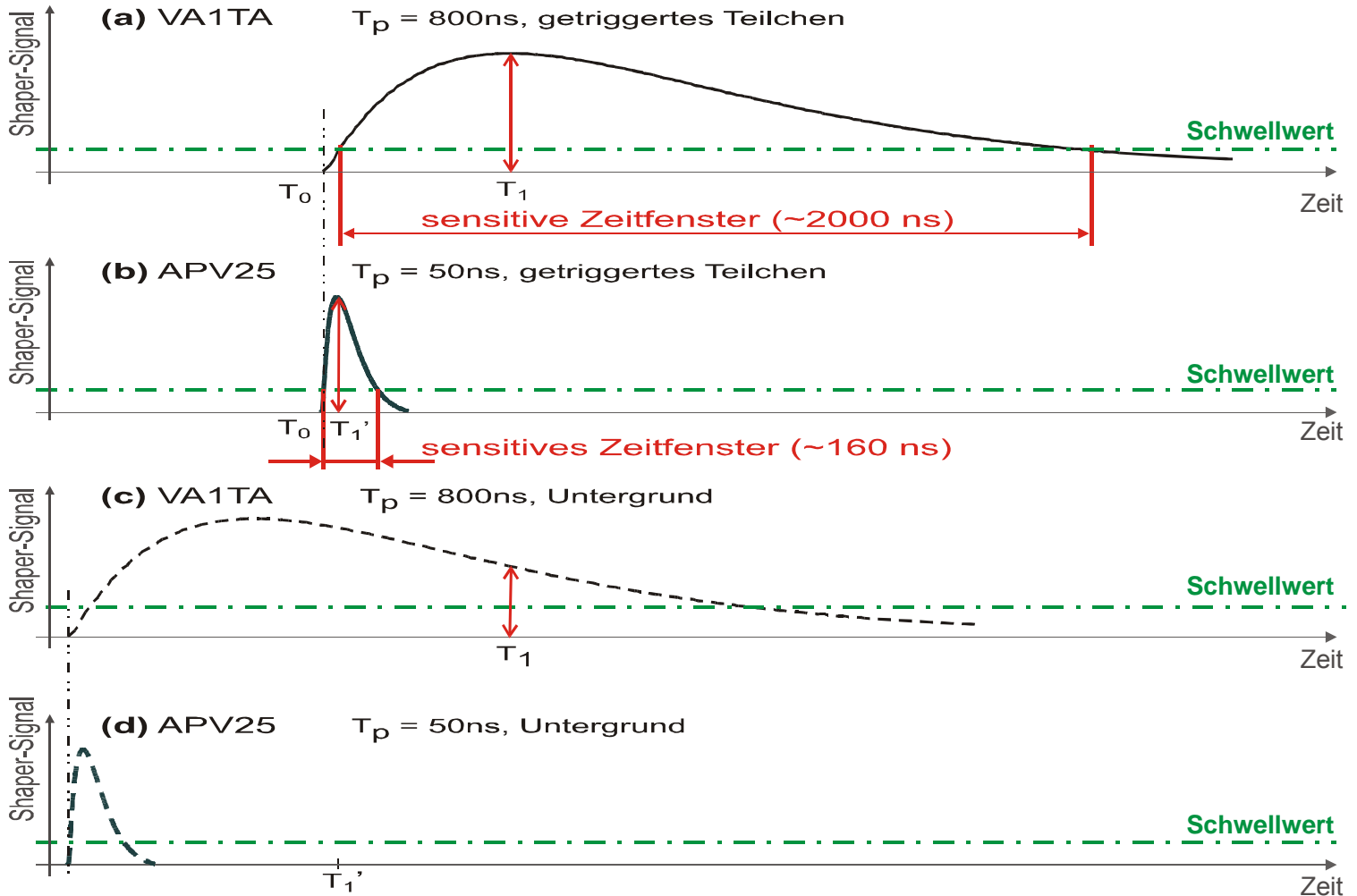
# BACKUP SLIDES

## 2D-Clustering



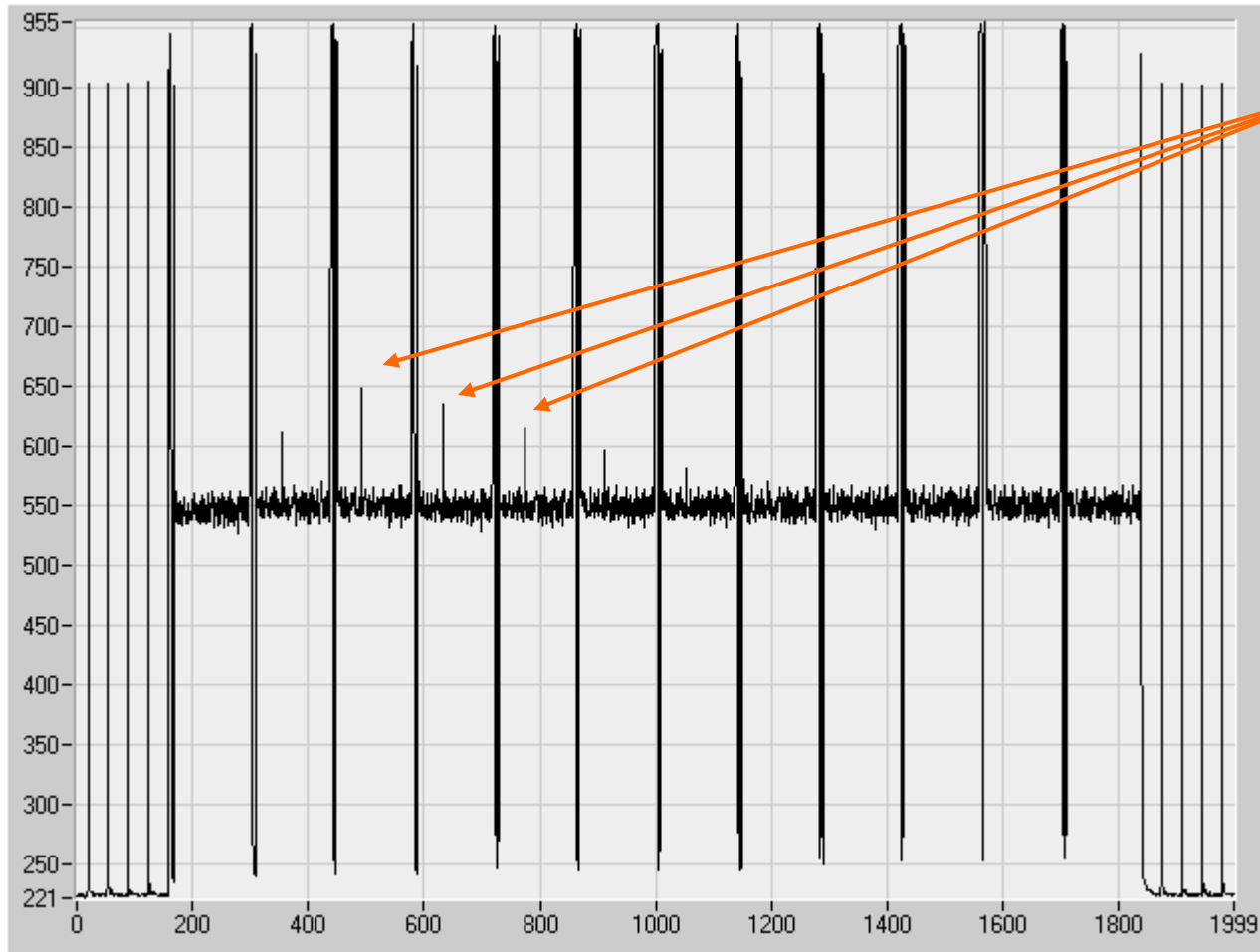
- 2 Steps:**
- ⊗ Search for neighbouring strips above threshold and mark them in a hit map.
  - ⊗ Search continuous areas (clumps) and calculate outline.

# Occupancy-Reduktion – Principle



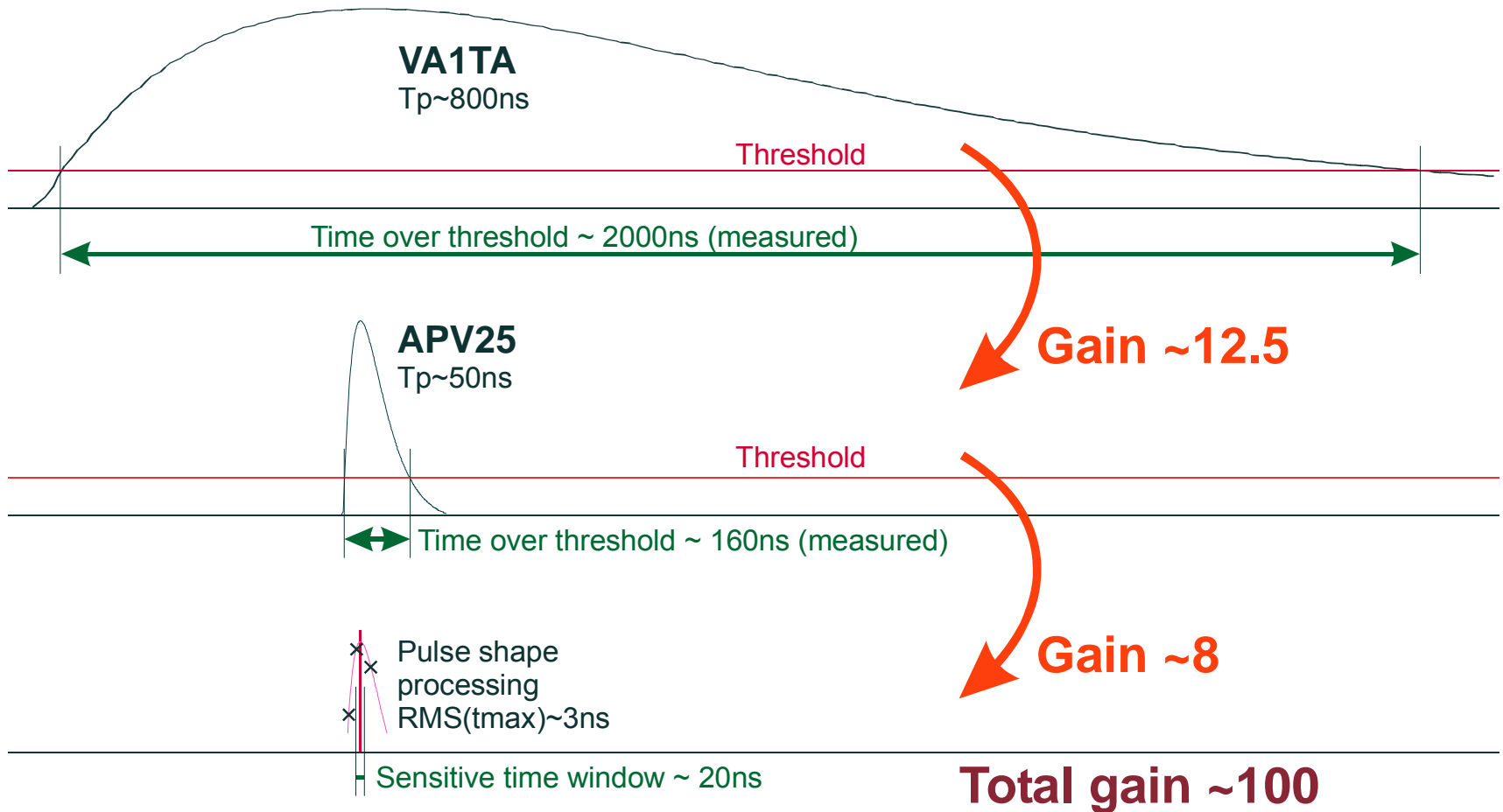


## Multipeak Mode



Particle signal

# Occupancy-Reduktion – Hit Time Reconstruction



# APV25

